

Notice of References Cited	Application/Control No. 10/625,238		Applicant(s)/Patent Under Reexamination XUE, YALEI	
	Examiner Jean F. Duverne		Art Unit 2839	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,431,919	08-2002	Wang et al.	439/680
*	B	US-6,354,884	03-2002	Yeh et al.	439/680
*	C	US-6,312,293 B1	11-2001	Wang, Suiya	439/677
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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